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**10/607,840**

**June 27, 2004**

**Gregory R. Hanson**

2877

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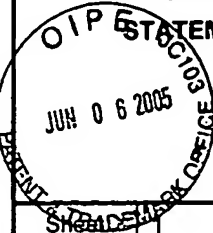
**UBAT1490-2**

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Examiner Initials	Cite No.	FOREIGN PATENT DOCUMENTS			Publication Date MM-DD-YYYY (Number 43)	Name of Patentee or Applicant of Cited Document
		Country Code	Number	Kind Code (if known)		

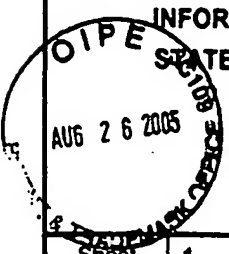
PATRICK CONNALLY

11.29.2005

<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b> 		Application Number	10/607,840	
		Filing Date	June 27, 2003	
		First Named Inventor	Gregory R. Hanson	
		Group Art Unit	2877	
		Examiner Name		
Sheet 1	of 2	Attorney Docket Number	UBAT1490-2	
<b>NON-PATENT LITERATURE DOCUMENTS</b>				
Examiner Initials	Cite No.	Citation		
PJC		International Search Report from PCT/US2004/012710, January 7, 2005		
PJC		Written Opinion of the International Searching Authority from PCT/US2004/012710, January 7, 2005		
PJC		International Search Report from PCT/US2004/012798, February 16, 2005		
PJC		Written Opinion of the International Searching Authority from PCT/US2004/012798, January 7, 2005		
PJC		International Search Report from PCT/US2004/012618, February 21, 2005		
PJC		Written Opinion of the International Searching Authority from PCT/US2004/012618, February 21, 2005		
PJC		Mendoza Santoyo F. et al. "Multi-pulsed digital holography applied to full 3D measurements of dynamic events" Proceedings of the SPIE - The International Society for Optical Engineering SPIE-INT. SOC. OPT. ENG. USA, vol. 4420, 15 October 1999 (1999-10-15), pages 132-138, XP002311234 ISSN: 0277-786X		
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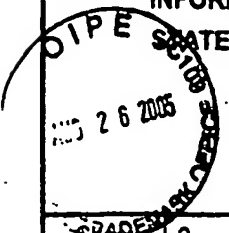
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pgc		Khare K et al. "Direct sampling and demodulation of carrier-frequency signals" Optics Communications, North-Holland Publishing Co. Amsterdam, NL, vol. 211, No. 1-6, 1 October 2002 (2002-10-01), pages 85-94, XP004382791 ISSN: 0030-4018			
pgc		Pedrini G. et al. "Quantitative evaluation of two-dimensional dynamic deformations using digital holography" Optics and laser technology, Elsevier Science Publishers BV., Amsterdam, NL, vol. 29, no. 5, July 1997 (1997-07), pages 249-256, XP004090206 ISSN: 0030-3992			
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